



CERTIFICATE OF CONFORMANCE

TEXAS INSTRUMENTS INCORPORATED
12500 TI BOULEVARD
DALLAS TX 75243
CAGE CODE 01295

Print Date 10-Jun-26
Est. Ship Date 16-Jun-26

Page 1 of 1

Ship To No. 183680

Sold To No. 183680

CENTUM ELECTRONICS LIMITED
#44, KHB INDUSTRIAL AREA
YELAHANKA NEWTOWN
BANGALORE
560106
INDIA

CENTUM ELECTRONICS LIMITED
#44, KHB INDUSTRIAL AREA
YELAHANKA NEWTOWN
BANGALORE
560106
INDIA

Packaging List:/
Delivery Document No
640626495

Customer Po No.
HRM251015

Sales Order No.
1031305234

Transfer Order No.
0007915877

Customer Part No./ Reference No.
S06CQT01005AA6-FM

Customer Revision No.

Material Entered
LM741 MD8

Item No.
000010

Qty To Ship.
2,000

Material Name
LM741 MD8

Material Description: Operational Amplifier

Texas Instruments Incorporated (TI) certifies that the products included in this shipment conform to TI's or other mutually agreed upon specifications, in accordance with TI's Terms of Sale. This certificate does not expand or modify the terms of TI's warranty as set forth in TI's Terms of Sale. This certificate is valid only to the original customer and is not transferrable.

Customer part number(s) referenced on this document are for customer internal use only unless conformance to the customer drawing has been agreed upon in writing by TI.

TI LOT NUMBER	LOT TRACE CODE	QUANTITY	DATE CODE	WAFER LOT	WAFER LTC	ASSEMBLY SITE
4162565CL4	43AJJ5I	2000	2412+5	4091573CU8	JM01B0972GF6	QAB

Latest Re-inspection Date

For Lot Number



AUTHORIZED REPRESENTATIVE

10-Jun-26

Date

Group C Summary Report

Lot Number: 4331987

Device Name: LM124AJRQMLV

Assembly Site: MMT

Lot Date Code: 2014-32-A

Wafer Lot Date Code: 2014-1Q-H-GL

Wafer Lot Number: 3011776

Parent Die: LM124

Die Attach: J

Window: 1Q 2014 to
1Q 2014

Pin: 14

Package: DIP

MCG: 49

Test Start: 10/22/2014

Test Complete: 10/22/2014

Sub-Group	Test	Method	Sample Size	Rejects / Data	Notes
C1	Steady-state life test	1005		0	1
C1	Endpoint Electrical Test		45	0	2

Notes:

- 1,000 hours/125C or equivalent. (If greater than 1,000 hours/125C enter actual conditions into comments below)
- Endpoint electrical testing in accordance with device test specification.

Comments:

File Attachment

Filename

Prepared By: Kim Suan Justina Lee

Prepared By Email: Justina.Lee@ti.com

Prepare Date: 10/21/2014